

DEC 09 2003  
TRADEMARK OFFICE

**FIG. 1**

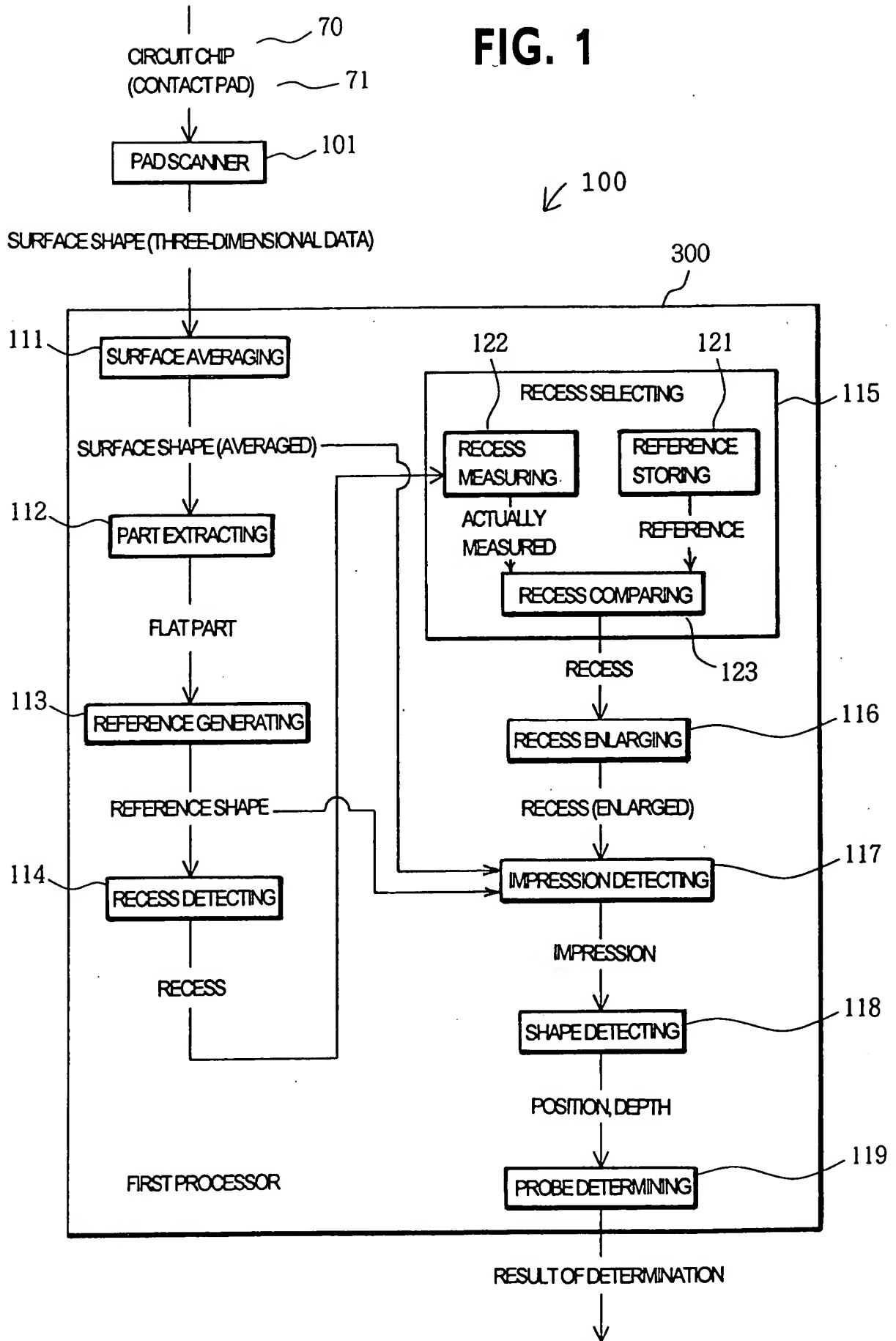
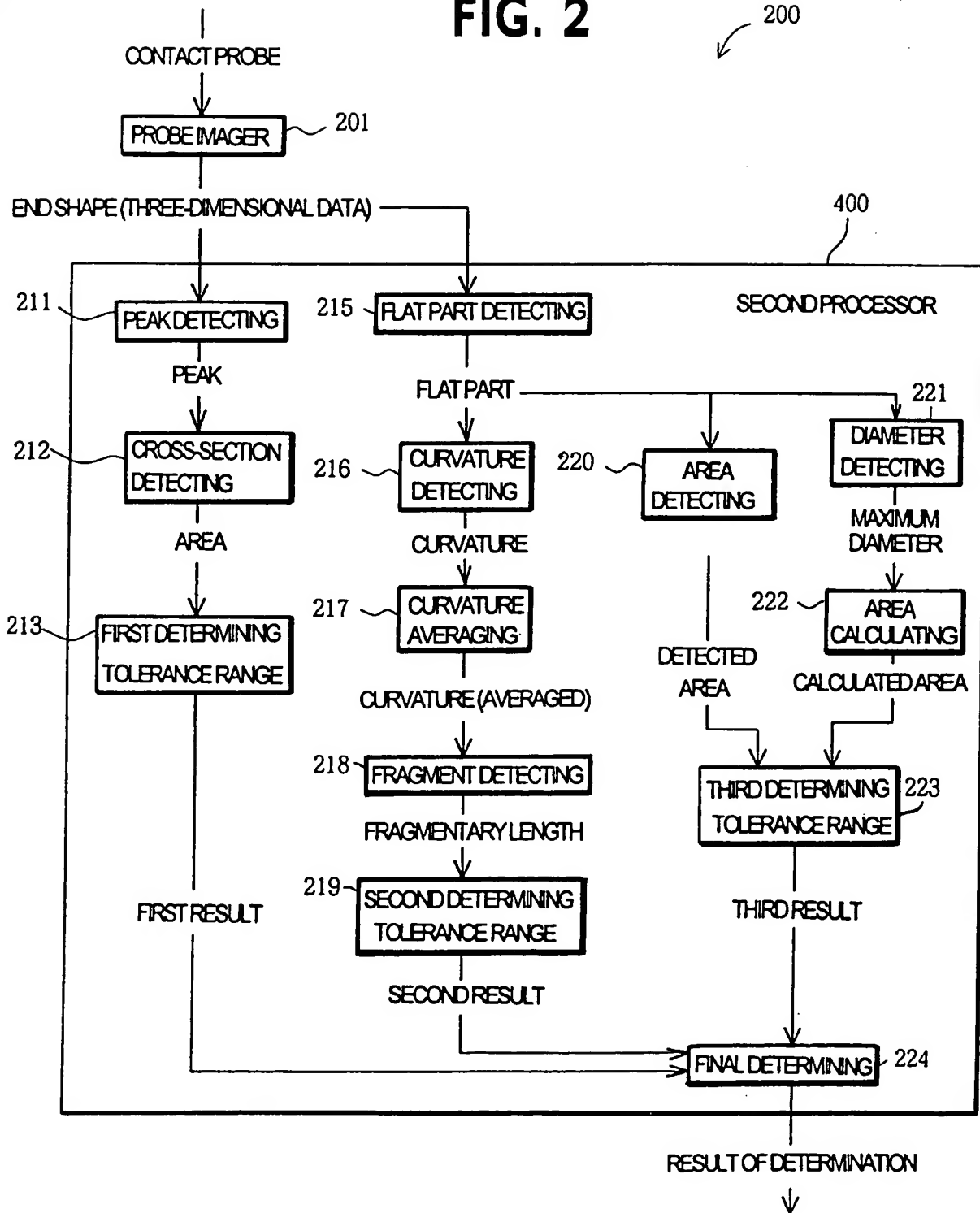


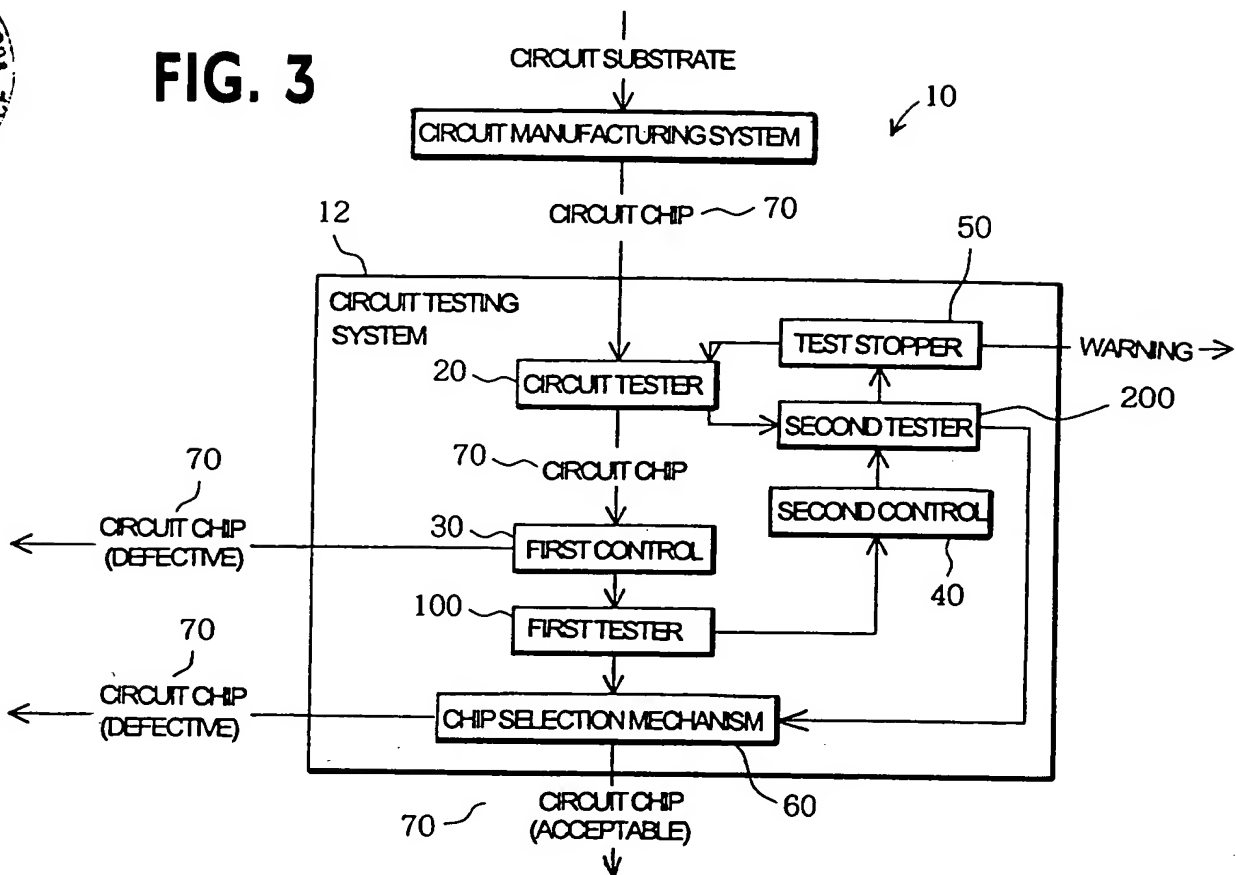


FIG. 2

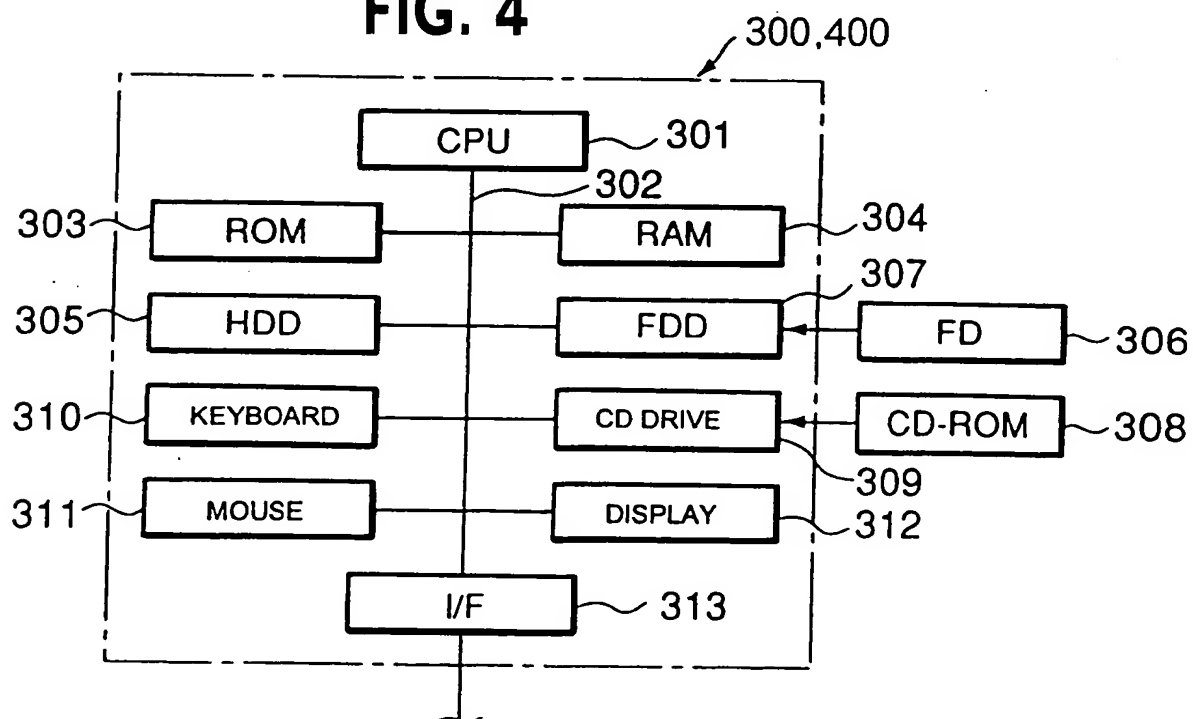




**FIG. 3**

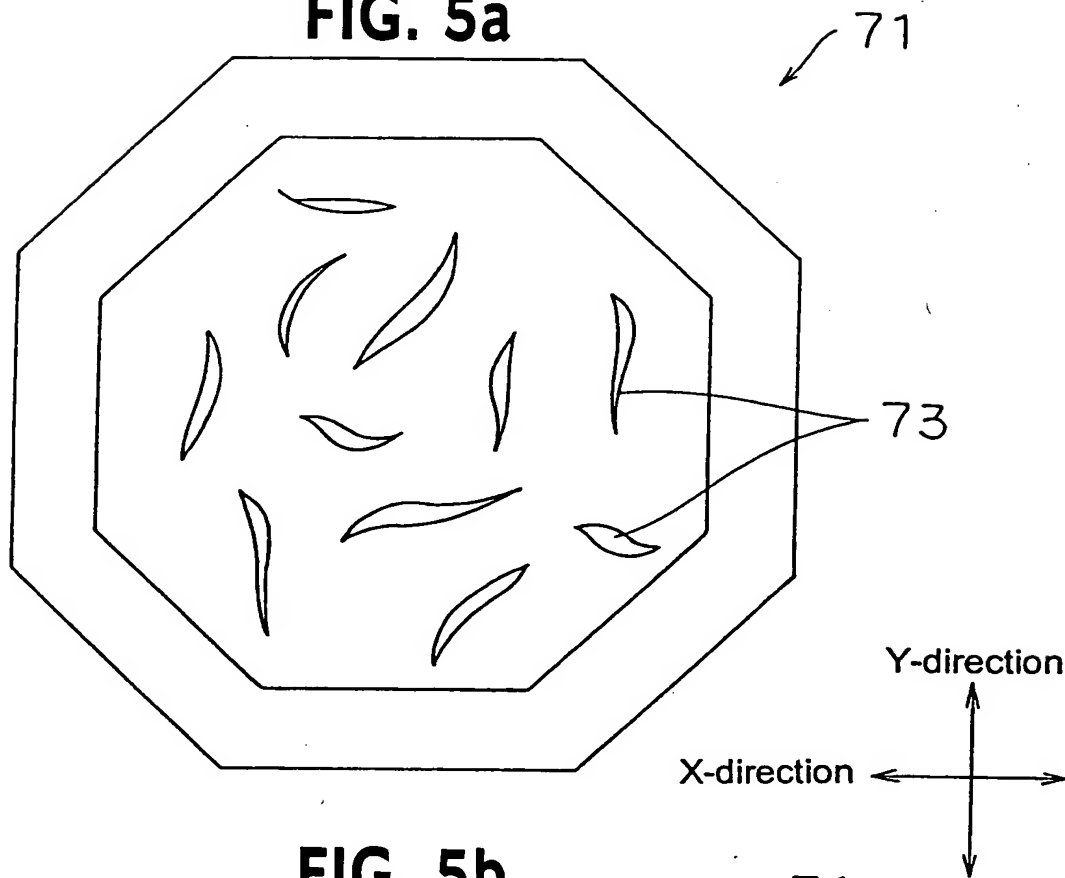


**FIG. 4**

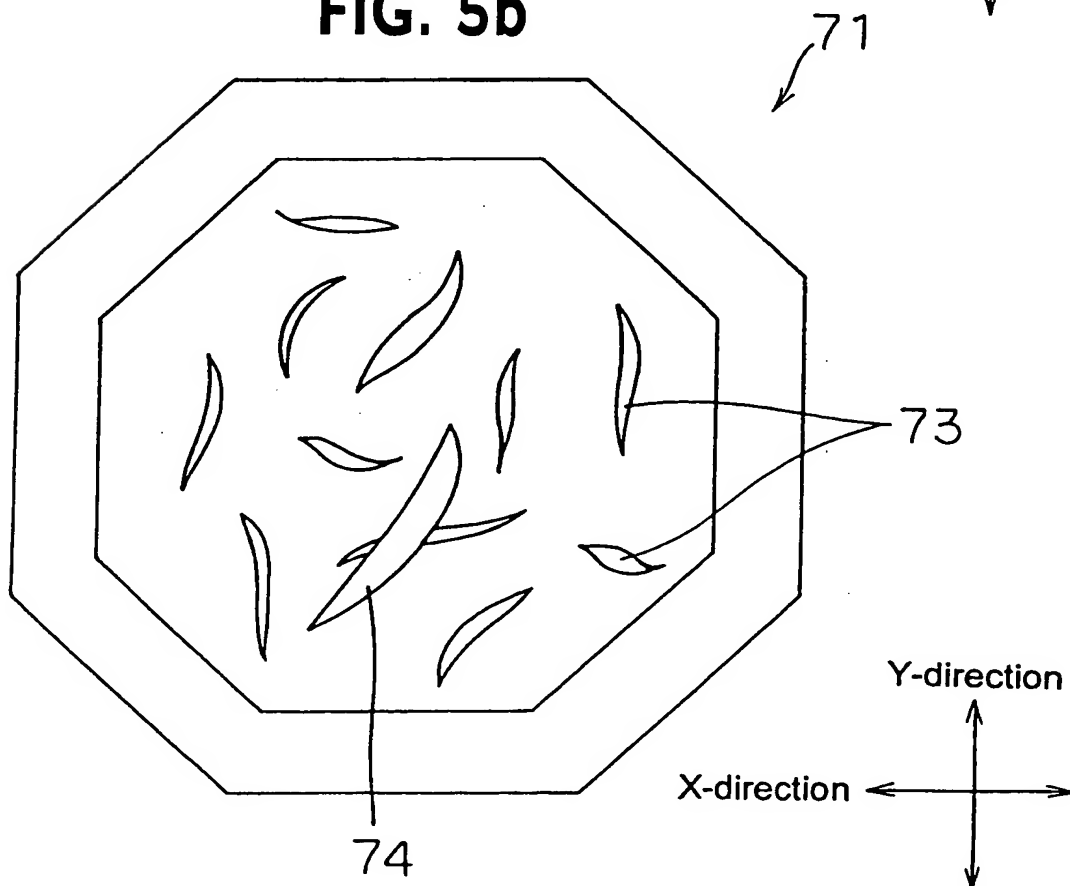




**FIG. 5a**



**FIG. 5b**

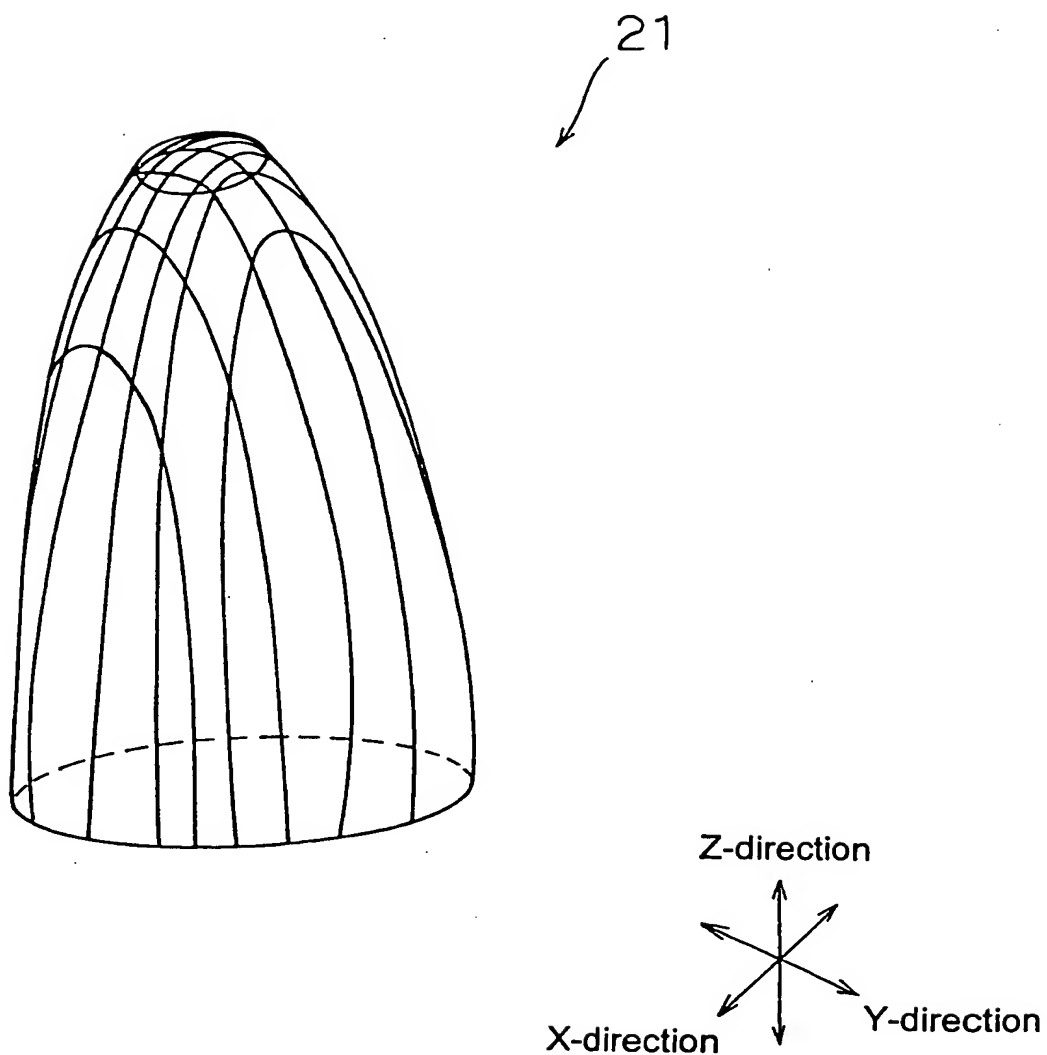


Title: PROBE TESTING METHOD AND  
APPARATUS FOR DETERMINING  
ACCEPTABLE/DEFECTIVE END SHAPE OF  
CONTACT PROBE THROUGH IMAGE  
ANALYSIS

Inventor(s): Yoshihiro SASAKI, et al.  
Appl. No.: 10/644,071



**FIG. 6**



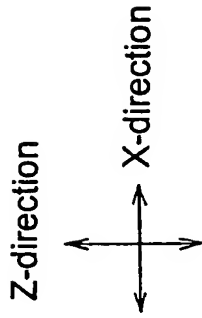


FIG. 7a



FIG. 7b



FIG. 7c



FIG. 7d



FIG. 7e

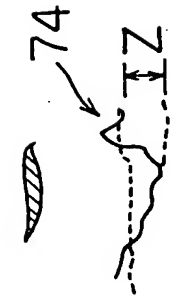


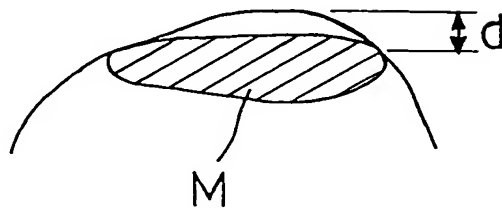
FIG. 7f



FIG. 7g



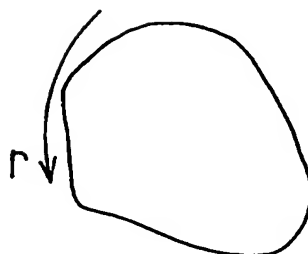
**FIG. 8a**



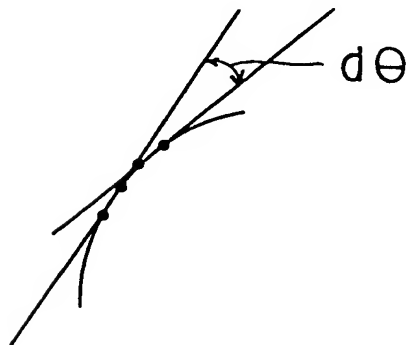
**FIG. 8b**



**FIG. 9a**



**FIG. 9b**



**FIG. 9c**

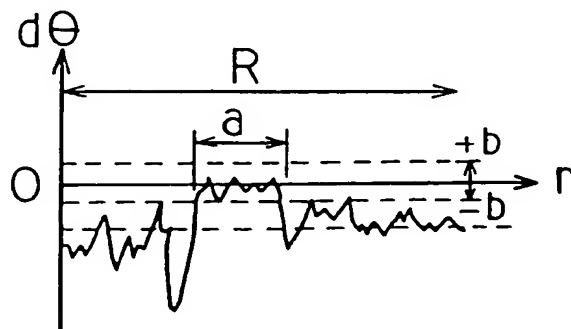
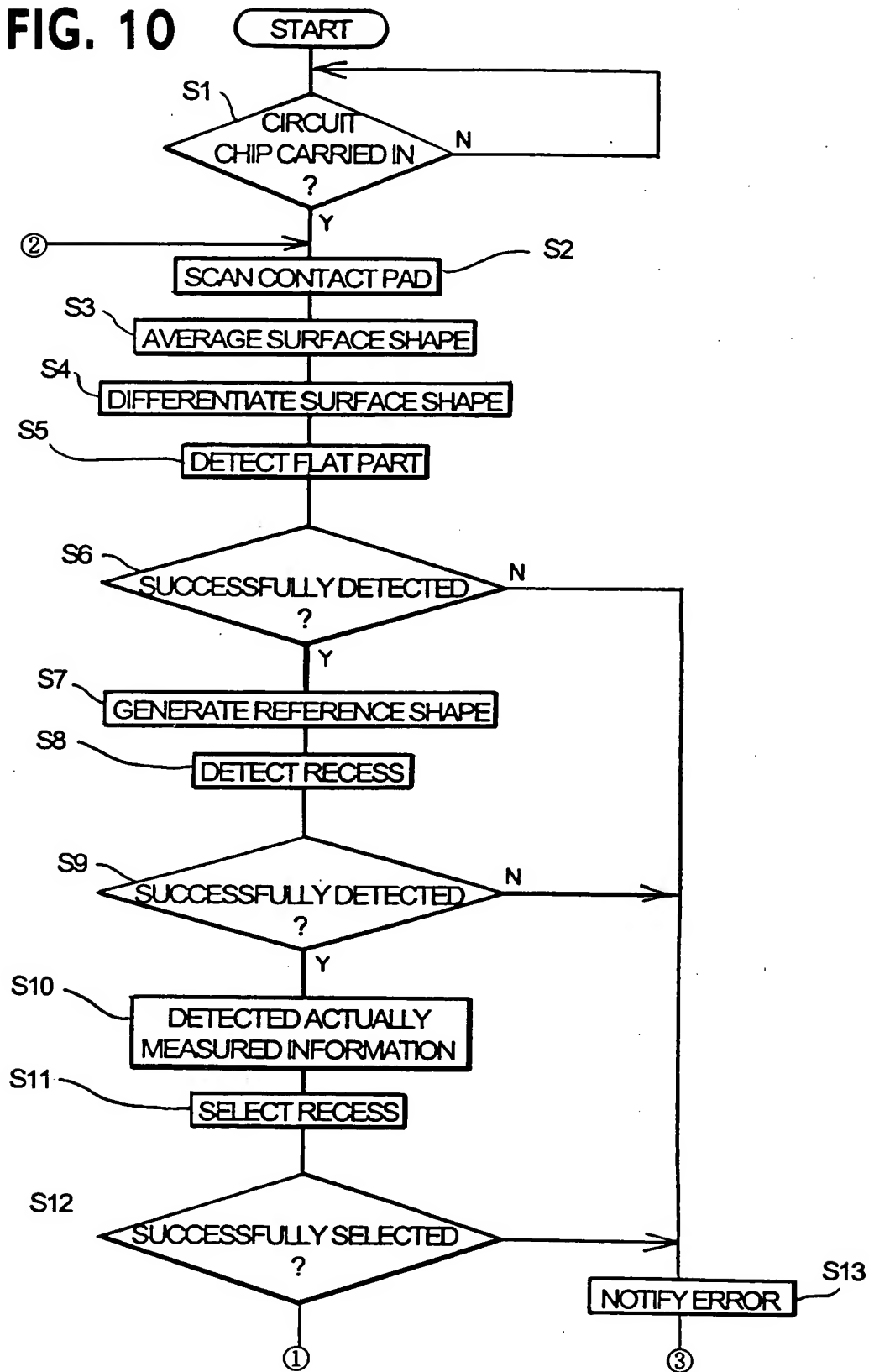


FIG. 10





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FIG. 11

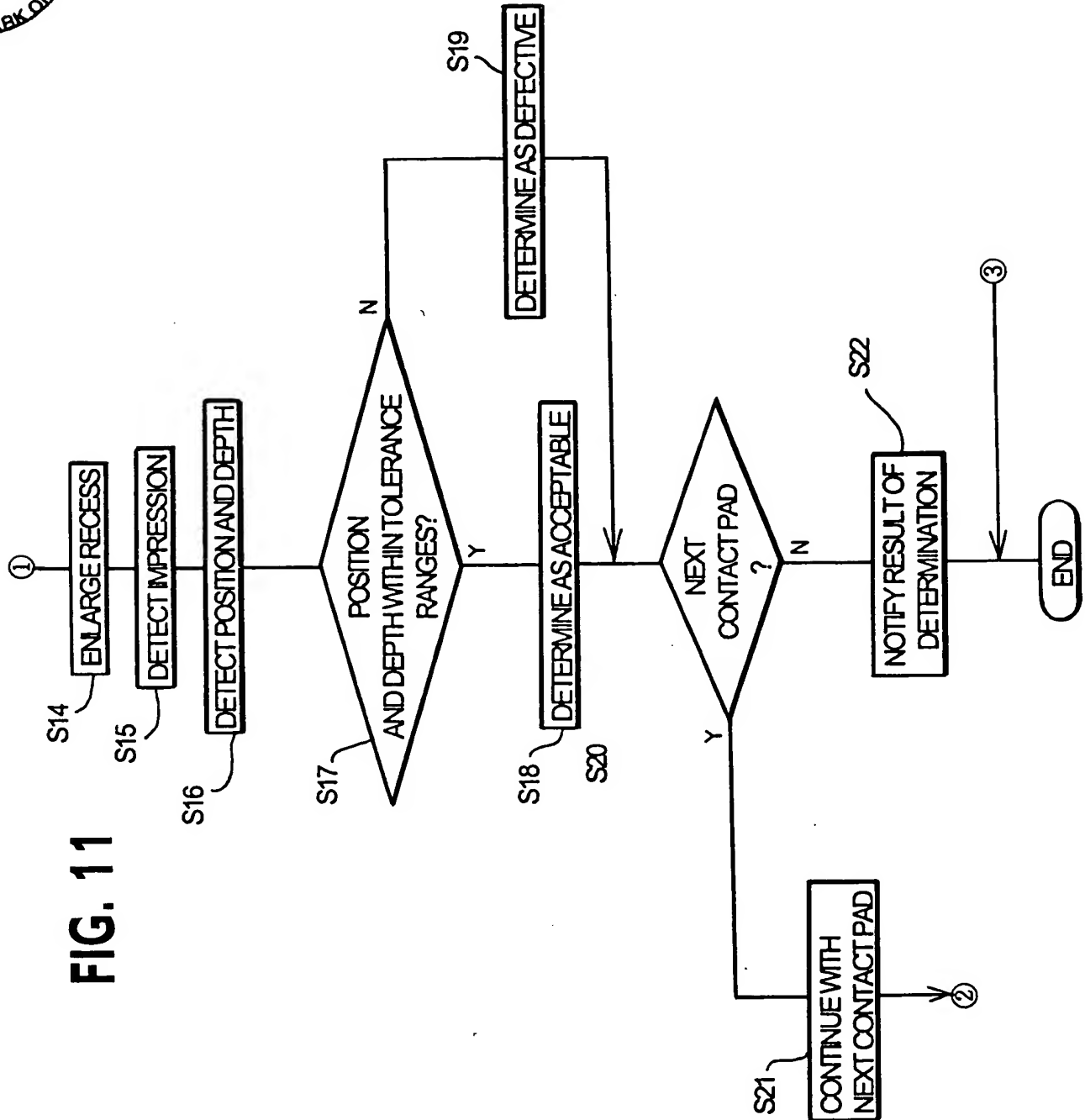




FIG. 12

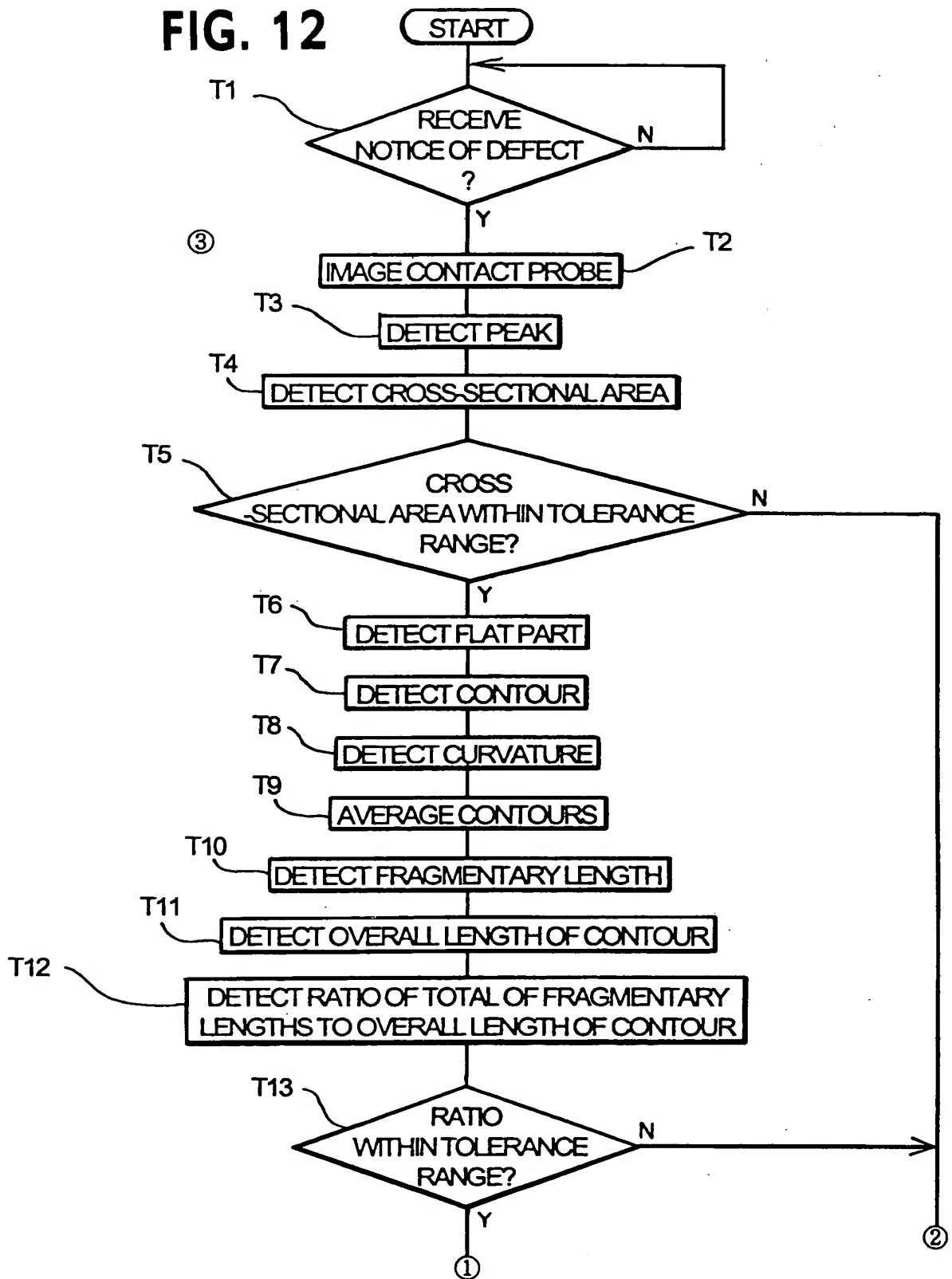




FIG. 13

